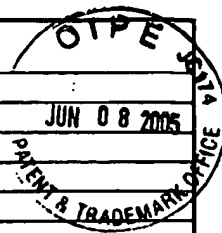


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Sheet		1	of	21	Application Number 10/031,073
					Filing Date January 15, 2002
					First Named Inventor Nobuya Kitaguchi et al.
					Art Unit 1743
					Examiner Name Monique T. Cole
					Attorney Docket Number 7241-16



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. ¹	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS			
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MC		TAKEHIKO KITAMORI ET AL, "Thermal Lens Microscopy and Microchip Chemistry," Analytical Chemistry, February 1, 2004, pp. 53A-60A.	
I		KENJI UCHIYAMA ET AL., "Thermal Lens Microscope," Jpn. J. Appl. Phys. Vol. 39 (2000) pp. 5316-5322.	
		MASAAKI HARADA ET AL., "Photothermal Microscopy with Excitation and Probe Beams Coaxial under the Microscope and Its Application to Microparticle Analysis," Anal. Chem. 1993, 65, 2938-2940.	

Examiner Signature	<i>M. Cole</i>	Date Considered	8/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
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